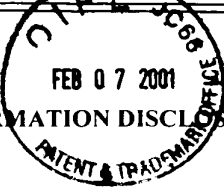


Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Atty Docket 0756-2062		Serial No. 09/433,705	
 INFORMATION DISCLOSURE STATEMENT				Applicants: Shunpei YAMAZAKI			
				Filing Date: November 04, 1999		Group Art Unit: 2811	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
Loke	5,949,107	09/07/1999	Zhang				
Loke	6,001,714	12/14/1999	Nakajima et al.				
Examiner <i>Loke</i>			Date Considered <i>1/26/02</i>				
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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U.S. Department of Commerce
Patent and Trademark Office

Atty Docket 0756-2062

Serial No. 09/433,705

INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI

Filing Date: November 04, 1999

Group Art Unit: 2811

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
Loke	09-293600 J	11/11/1997	JP			Eng Abst	

Examiner

Loke

Date Considered

1/26/02

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Loke	6,001,714	12/14/1999	Nakajima et al.			

TECHNICAL ROOM

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JUL 0 5 2001

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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
Loke	5,686,328	11/11/1997	Zhang et al.			
Loke	6,030,667	02/29/2000	Nakagawa et al.			

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No
Loke	09-293600	11/11/1997	JP			X

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner Initial	
Loke	Specification and Drawings, of U.S. Patent Application, 09/714,891, filed, November 17, 2000
Loke	Specification and Drawings, of U.S. Patent Application, 09/619,732, filed, July 19, 2000
Loke	Specification and Drawings, of U.S. Patent Application, 09/618,930, filed, July 18, 2000

Examiner Loke Date Considered 1/26/02

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07/05/2001

Form PTO-1449
(Rev. 8-83)

U.S. Department of Commerce
Patent and Trademark Office

Atty Docket 0756-2062

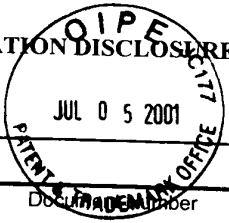
Serial No. 09/433,705

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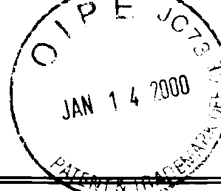
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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Examiner Loke Date Considered 1/26/02

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Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No.: 0756-2062		Serial No.	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Applicant:			
				Filing Date:		Group:	
U. S. PATENT DOCUMENTS							
Examiner Initial		Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date (if approp.)
Loke		5,643,826	07/01/97	Ohtani et al.			
↓		5,923,962	07/13/99	Ohtani et al.			
↓		5,247,190	09/21/93	Friend et al.			
Loke		5,399,502	03/21/95	Friend et al.			
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		Document Number	Date	Country	Class	Subclass	Translation Yes No
Loke		07-130652	05/19/95	Japan			Abst.
↓		08-078329	03/22/96	Japan			Abst.
↓		10-135468	05/22/98	Japan			Abst.
↓		10-135469	05/22/98	Japan			Abst.
↓		10-294280	11/04/98	Japan			Abst.
↓		11-191628	07/13/99	Japan			Abst.
↓		10-92576	04/10/98	Japan			Abst.
Loke		WO 90/13148	11/01/90	PCT			English
OTHER DOCUMENTS (Including Author, Title, Relevant Pages, Date, Place of Publication)							
Loke		Shimokawa et al., Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement, Japanese Journal of Applied Physics, Vol. 27, No. 5, May, pp. 751-758, 1988.					
Loke		Hatano et al., A Novel Self-Aligned Gate-Overlapped LDD Poly-Si TFT With High Reliability and Performance, IEDM Technical Digest 97, pp. 523-526					
Loke		Hermann Schenk et al., Polymers for Light Emitting Diodes, EuroDisplay '99 Proceedings, pp. 33-37					
Examiner Loke				Date Considered 1/26/02			
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